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LIST OF RELEVANT ART CITED BY APPLICANT (Use several sheets if necessary)	Applicants: Michael R. Rice, et al	
	Filing Date: January 26, 2004	Group: 2125

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Charles Kay	12/9/05

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Charles Kasey	12/9/05

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Examiner Charles Kim — Date Considered 12/9/05

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with your communication to applicant.

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U.S. Department of Commerce, Patent and Trademark Office	Docket No.: 8201/Y01/SYNX/JW	Serial No.: 10/764,620
LIST OF RELEVANT ART CITED BY APPLICANT (Use several sheets if necessary)	Applicants: Michael R. Rice, et al	
	Filing Date: January 26, 2004	Group: 2125

U.S. Patent Documents

*Examiner Initial		Document Number	Issue Date	Name	Class	Subclass	Filing Date If Appropriate
	US-12						
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	US-14						
	US-15						
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	US-17						
	US-18						
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	US-22						

Foreign Patent Documents

		Document Number	Date	Country	Class	Subclass	Translation Yes	Translation No
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Examiner Chuck Kendall | Date Considered 12/9/05

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Examiner: Charles Kasz — Date Considered: 12/9/05

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U.S. Department of Commerce, Patent and Trademark Office	Docket No.: 8201/SYNX/JW	Serial No.: 10/764,620
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	Filing Date: January 26, 2004	Group: 2125

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Examiner: Chuck Kay — Date Considered: 12/9/05

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